Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,242	CHIN ET AL.	
Examiner	Art Unit	
Temica M Beamer	2681	

SEARCHED					
Class	Subclass	Date	Examiner		
455	414.1	7/23/2005	ТМВ		
455	405	7/23/2005	TMB		
455	406	7/23/2005	ТМВ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
					

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DATE	EXMR
7/23/2005	ТМВ
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